PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant :	Scott A. Lerner	Docket No. :	IL-11179
Serial No. :		Art Unit :	
Filed :		Examiner :	
For :	COMPACT CATADIOPTRIC IMAGING SPECTROMETER UTILIZING REFLECTIVE GRATING		

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Alexandria, VA 22313-1450

Dear Sir:

Forwarded herewith is an Information Disclosure Statement, Form-1449, in the above-identified application. Copies of the cited references are enclosed: 14 U.S. Patent Documents and 1 Foreign Patent Document.

The above-mentioned disclosures, which are not admitted as prior art, are identified on the enclosed Form 1449.

Respectfully submitted,

Dated: October 2, 2003

Eddie E. Scott
Attorney for Applicant
Registration No. 25,220

Enclosures: As noted above

Please type a plus sign (+) inside this box +

PTO/SB/08A (08-00)
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet 1 of 1

Complete if Known	
Application Number	
Filing Date	
First Named Inventor	Scott A. Lerner
Group Art Unit	
Examiner Name	
Attorney Docket Number	IL-11179

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.[1]	U.S. Patent Document Number	Kind Code[2] (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		5,127,728		Warren, et al.	07-07-1992	
		5,717,487		Davies	01-10-1998	
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FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.[1]	Foreign Patent Document Office[3]	Number[4]	Kind Code[5] (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T[6]
			WO 99/63311		Ansley, et al.	12-09-1999		

Examiner Signature		Date Considered	

Examiner: initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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[1] Unique citation designation number. [2] See attached Kinds of U.S. Patent Documents. [3] Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). [4] For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. [5] Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. [6] Applicant is to place a check mark here if English language Translation is attached.
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